

Notice of References Cited	Application/Control No. 09/651,031	Applicant(s)/Patent Under Reexamination HUMMEL ET AL.	
	Examiner Sunray Chang	Art Unit 2123	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,796,617 ✓	08-1998	St. Ville, James A.	700/98
	B	US-5,289,567 A ✓	02-1994	Roth, James W.	345/420
	C	US-5,774,124 A ✓	06-1998	Itoh et al.	345/423
	D	US-5,542,030 A ✓	07-1996	Gutfinger, Ron S.	345/423
	E	US-5,492,002 A ✓	02-1996	Higgins et al.	73/1.14
	F	US-5,315,537 A ✓	05-1994	Blacker, Teddy D.	716/20
	G	US-4,933,889 ✓	06-1990	Meshkat et al.	716/20
	H	US-5,594,651 ✓	01-1997	St. Ville, James A.	700/98
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Peter Budgell, Oct 1998, ANSYS, "Finite Element Analysis MOdeling Issues and Ideas"
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Tle